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By: Linda Shaffer

D Lawrence
#9/a
1/21/03
PATENT
Attorney Docket No.: 18564-005810

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Chang-Meng Hsiung

Application No.: 09/660,138

Filed: September 12, 2000

For: MEASURING CONDUCTING
PATHS USING INFRARED
THERMOGRAPHY

Examiner: Brian J. Sines

Art Unit: 1743

AMENDMENT

Assistant Commissioner for Patents
Washington, D.C. 20231

Sir:

In response to the Office Action mailed September 11, 2002, please amend the above-identified application as follows. A petition for a one-month extension of time accompanies this response.

IN THE CLAIMS:

Please amend claims 19 and 22 as follows:

- Q1*
- 1 19. (Amended) A method for monitoring the quality of a sensor,
 - 2 comprising:
 - 3 applying a voltage to said sensor to cause said sensor to dissipate energy;
 - 4 capturing an image of said sensor with an infrared camera to generate a
 - 5 thermographic image of said sensor while said sensor is dissipating energy;

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